

Probing the molecular structure of antimicrobial peptide-mediated silica condensation using X-ray photoelectron spectroscopy

D. Matthew Eby, Kateryna Artyushkova, Anant K. Paravastu, and Glenn R. Johnson

ELECTRONIC SUPPLEMENTARY INFORMATION TABLE OF CONTENTS	PAGE
Total elemental XPS survey of KSL and KSL-Si	S-2
AFM images of KSL-Si nanoparticles	S-3

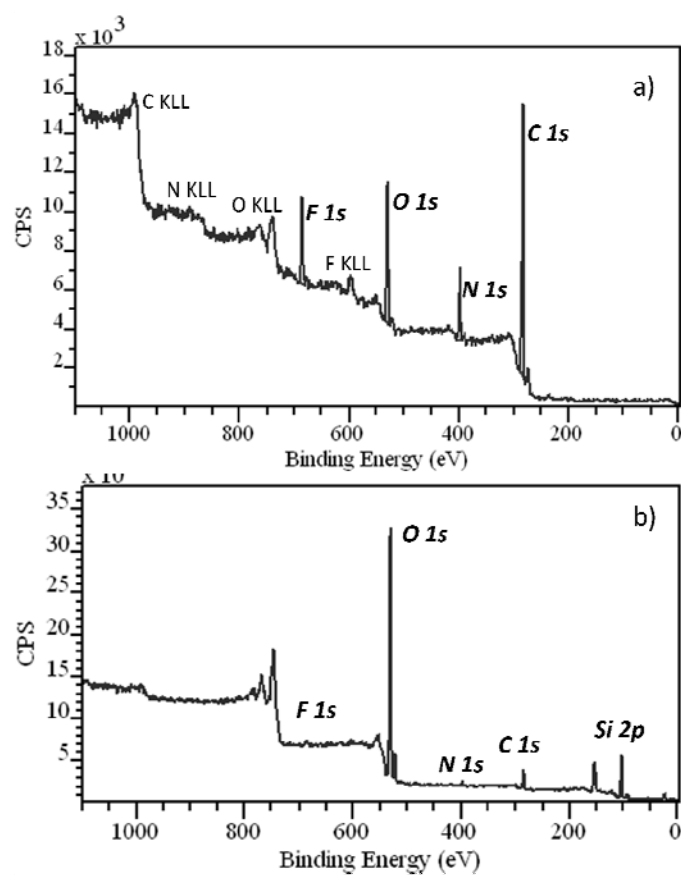


Figure S1. Typical XPS survey of KSL (a) and KSL-Si (b). Intensity (y-axis) units are counts per second (CPS) $\times 10^3$.



5

Figure S2. Atomic force microscope (AFM) image of KSL-Si nanoparticles. AFM images were obtained using a Nanoscope V, equipped with a Multimode V scanning probe microscope and a PicoForce stage (Veeco Instruments Inc, Woodbury, NY). A few microliters of KSL-Si suspension in 10 water was spread onto 5 mm square silicon wafers and dried at 37°C for 5 min before imaging in tapping mode, using an etched phosphorous (n)-doped silicon cantilever probe (type RTESP, Veeco).

15

20